

INTERNATIONAL STANDARD

NORME INTERNATIONALE



Microspeakers

Micro-haut-parleurs



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Microspeakers

Micro-haut-parleurs

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MICROSPEAKERS

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The text of this International Standard is based on the following documents:

CDV	Report on voting
100/3107/CDV	100/3211/RVC

All information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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MICROSPEAKERS

1 Scope

This document specifies the characteristics of microspeakers as well as the relevant test methods on microspeakers using steady-state sinusoidal signals, sinusoidal chirp, multi-tone or noise. The main characteristics include, but are not limited to, impedance, displacement, amplitude frequency response, distortion, and power handling.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60268-1, *Sound system equipment – Part 1: General*

IEC 60268-2, *Sound system equipment – Part 2: Explanation of general terms and calculation methods*

IEC 60268-21:2018, *Sound system equipment – Acoustical (output based) measurement*

IEC 60268-22:2020, *Sound system equipment – Electrical and mechanical measurements on transducers*

IEC 61260-1, *Electroacoustics – Octave-band and fractional-octave-band filters – Part 1: Specifications*

3 Terms, definitions and abbreviated terms

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1 Terms and definitions

3.1.1

microspeaker

loudspeaker, the radiating element (diaphragm or other radiator) of which is not greater than 40 mm

Note 1 to entry: The term "microspeaker" applies to the microspeaker unit (transducer) and also to passive microspeaker systems, which consist of one or more transducers provided with acoustical structures (e.g. chamber, port, aperture).

3.2 Abbreviated terms

HOHD higher-order harmonic distortion